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[54] REFLECTION INFRARED SURFACE DEFECT CORRECTION

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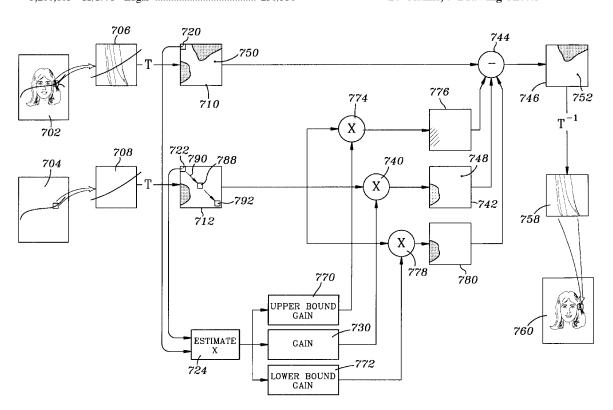
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[57] ABSTRACT

Surface defects in a reflection scan of a print made with visible light are corrected by using a scan of the print made with infrared light. This correction of surface defects is performed by controlling the intensity of defect detail in the infrared record by multiplying that defect detail by a gain. The gain varies for each region of the image as a function of the brightness of the image in that region. The gain approaches unity for white areas of the image, drops toward zero for darker areas, and approaches a small negative number for black areas of the image. The gain-multiplied defect detail is then subtracted from the visible image to create the corrected image free of the surface defects.

20 Claims, 9 Drawing Sheets



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